

A molecular dynamics study of swift heavy ion irradiation of amorphous silica: the role of thermal effects

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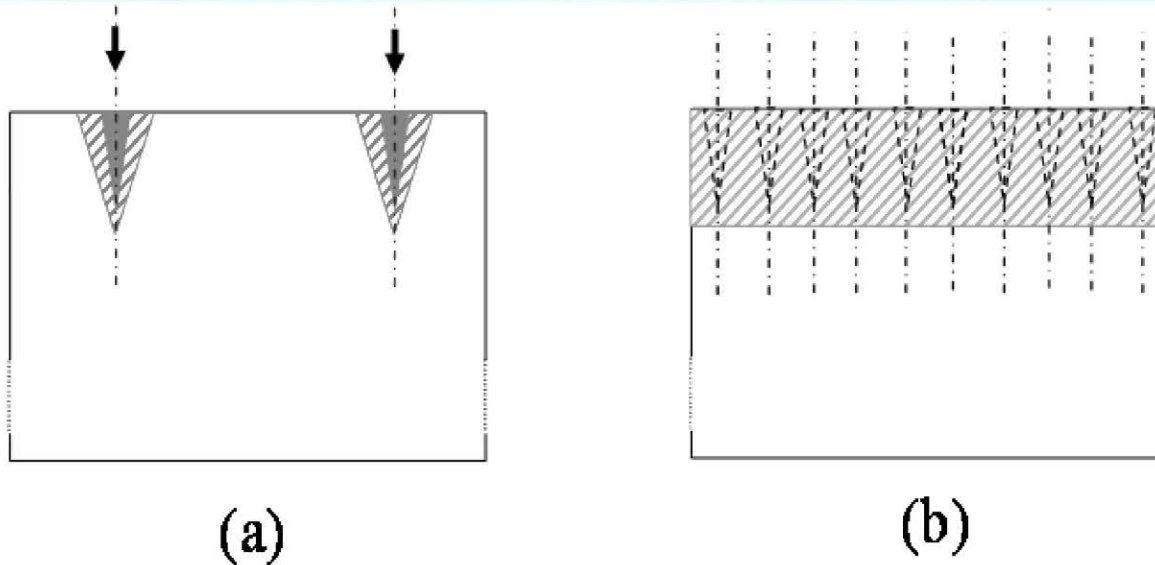
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"Ingeniamos el futuro"

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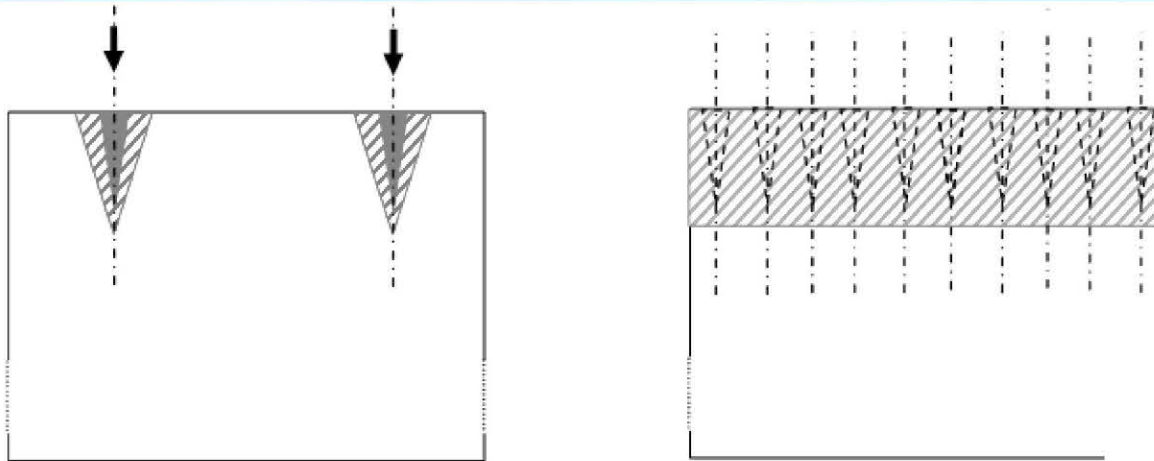


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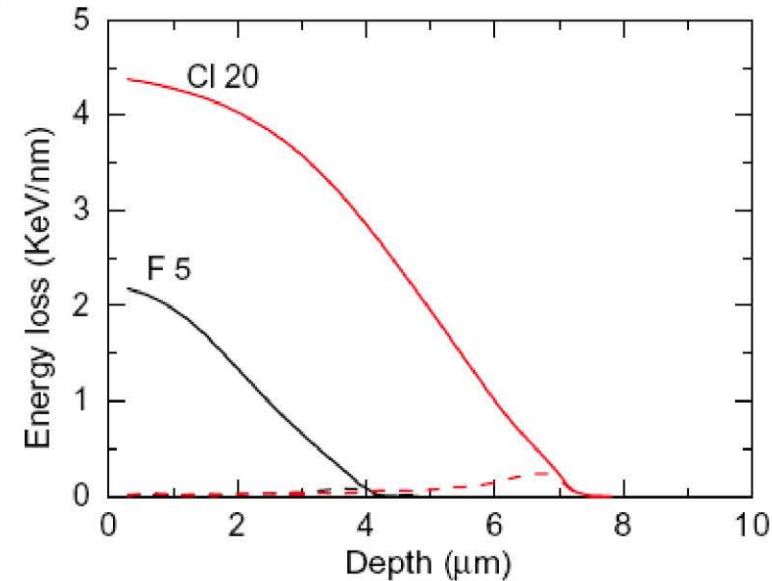
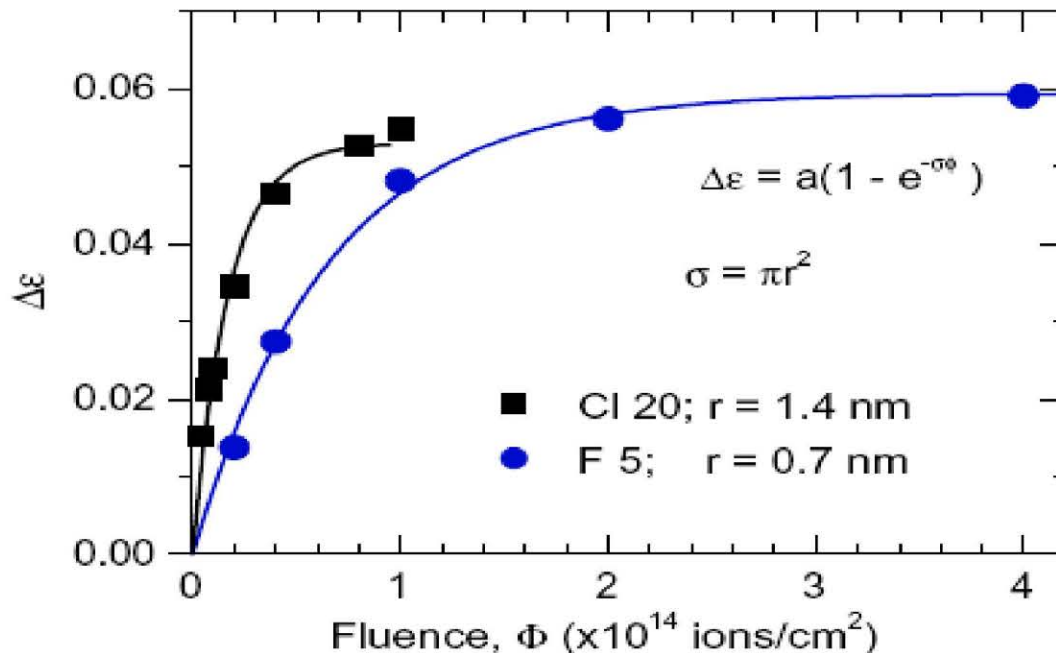


- Swift ion irradiation =>
 - Electronic sputtering
 - Density variation
 - Defect production
- Relevant effects in nuclear fusion

Amorphous silica

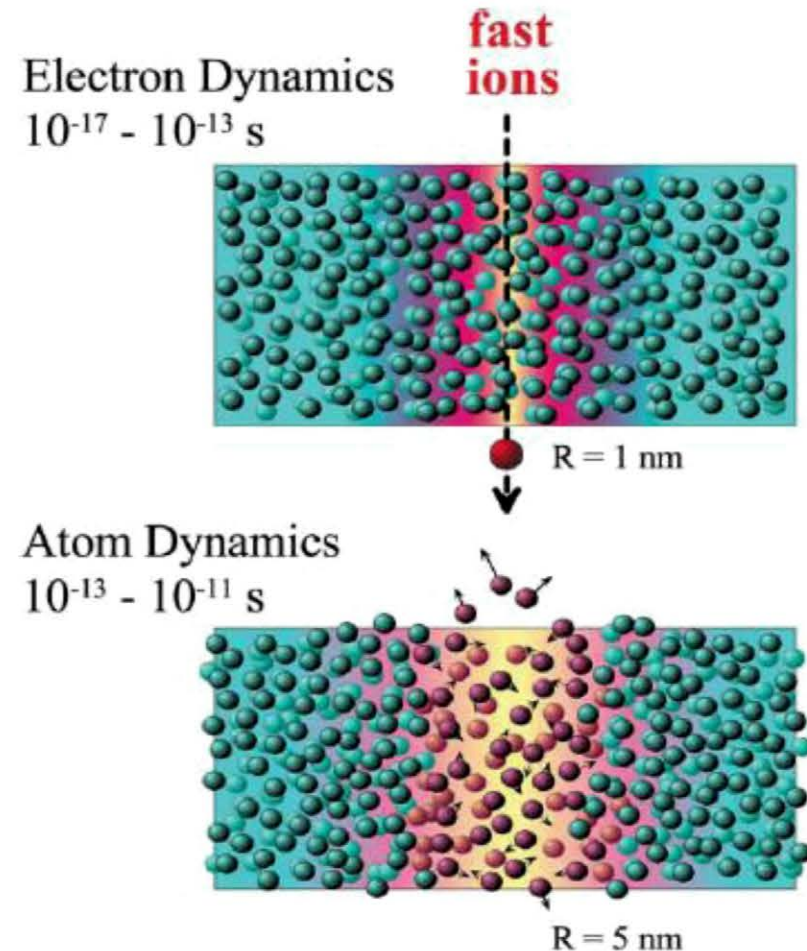


- Refractive index change
- Waveguides

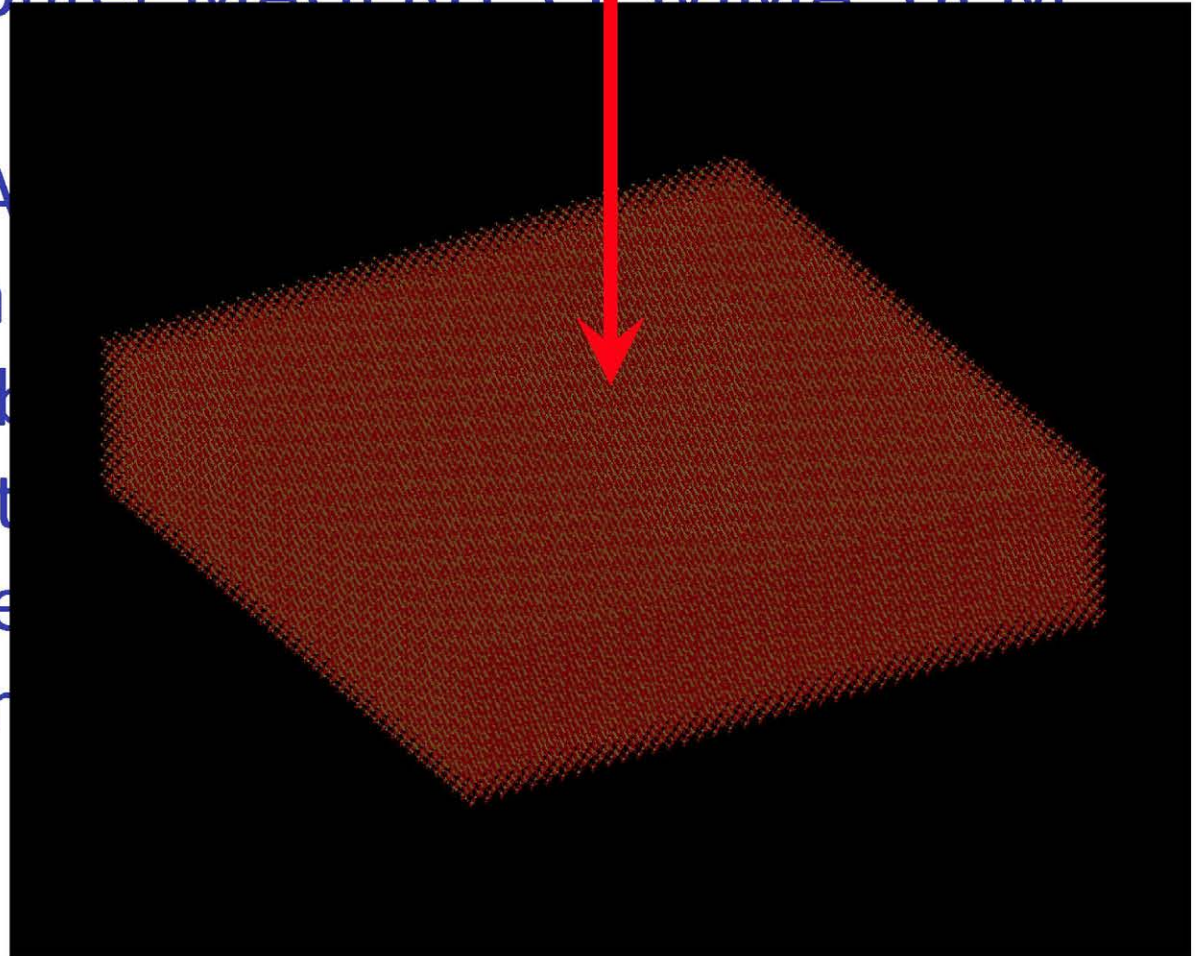


J. Manzano et al. NIMB 268, 3147

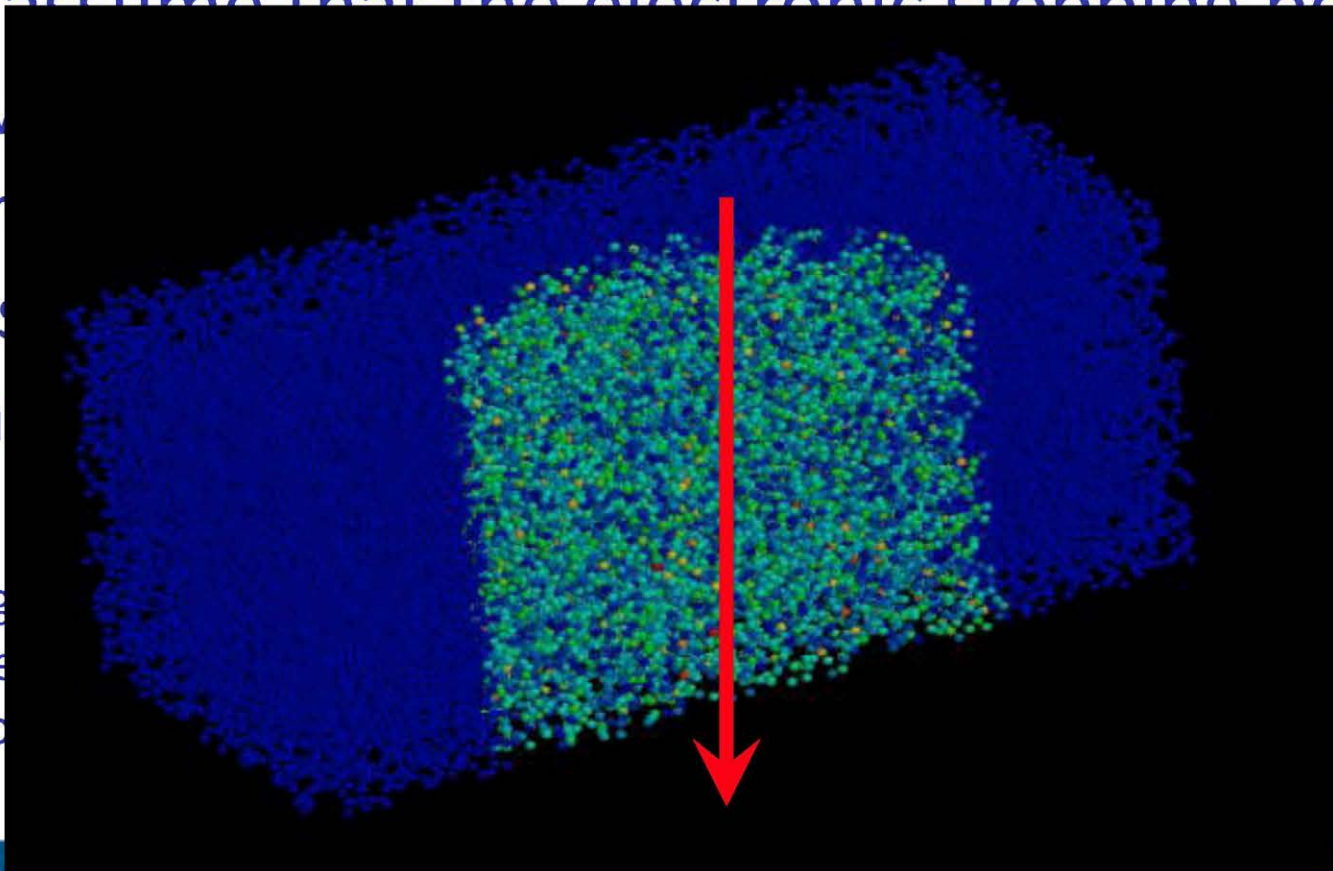
- Not well understood
- Permanent damage
- Modification of properties
- Defect annealing
- Nano-track formation
- Complex energy transfer mechanisms
- Goal: thermal effects by MD



- Super computer MAGERIT CESVIMA UPM
- Typical 512
- Code MDCA
- FG potential
- Simulation k
- Simulation t
- PBC in three
- 2 dimension



- Can't explain ion-solid energy transfer
- Our goal is to study thermal effects
- We assume that the electronic stopping power is even in a cylindrical geometry
- Substrate temperature like

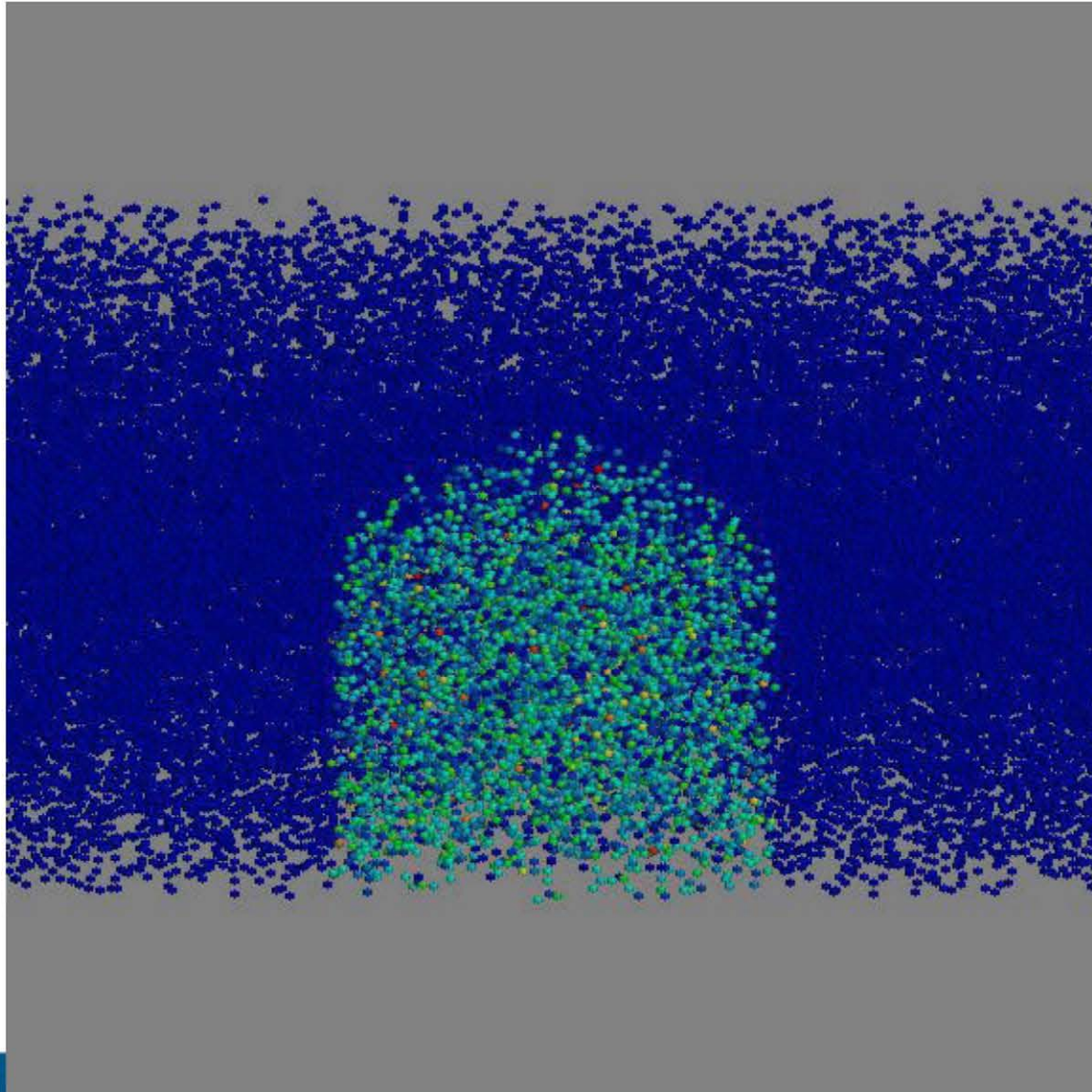


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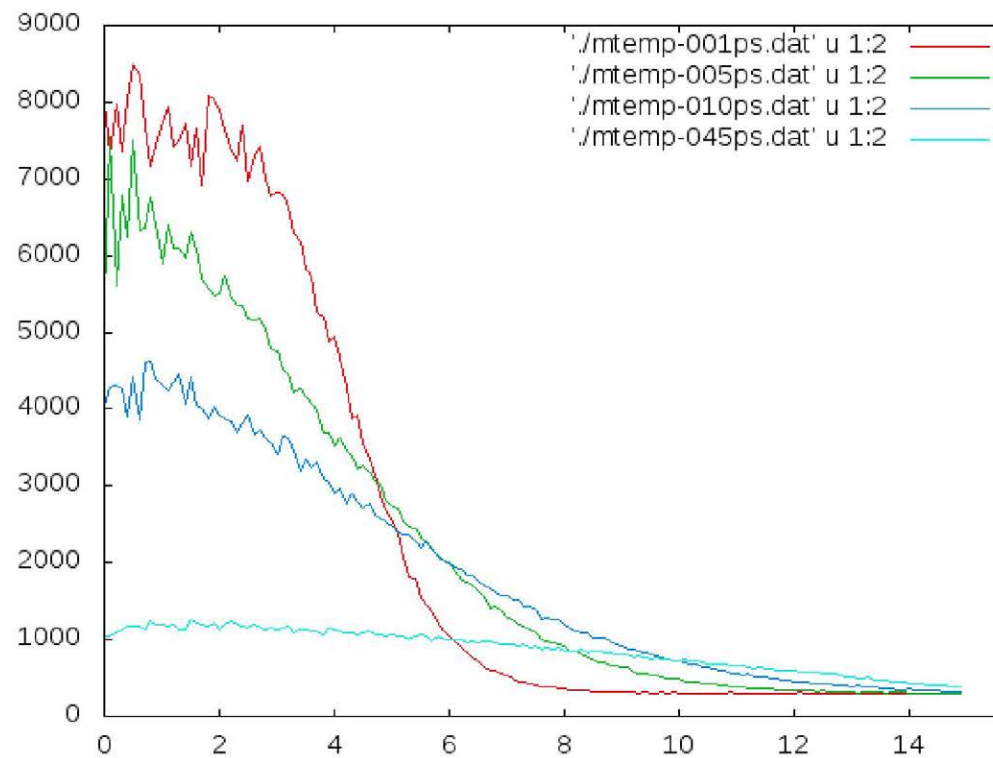
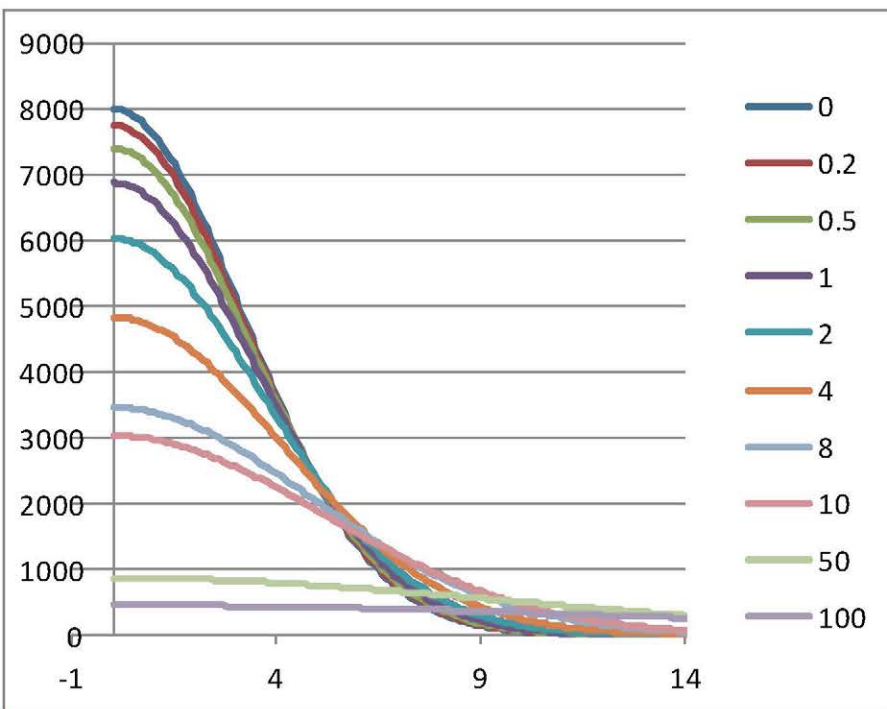
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MD



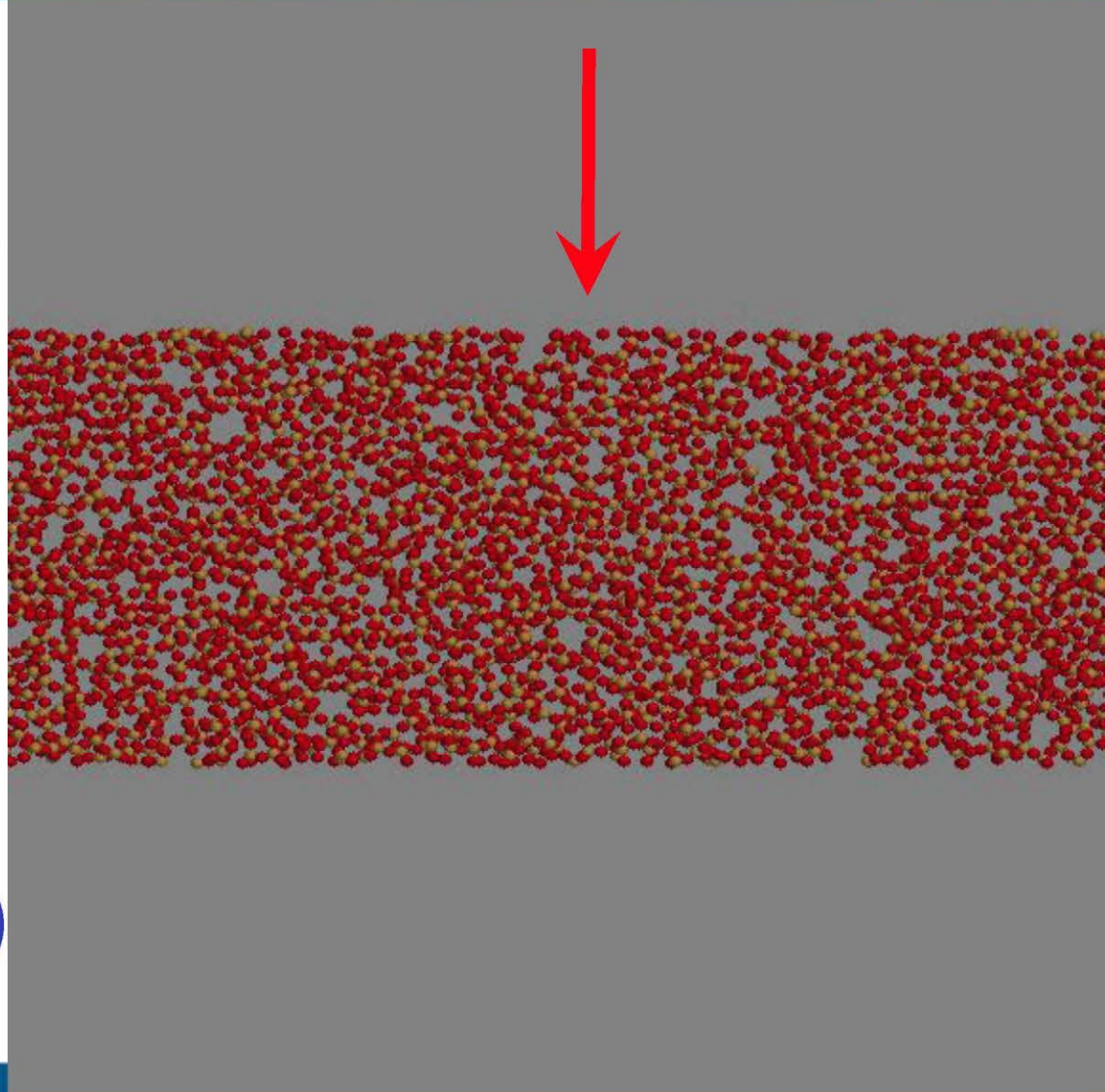
- Resulting temperature profiles compatible with electron MC simulations

10 keV/nm



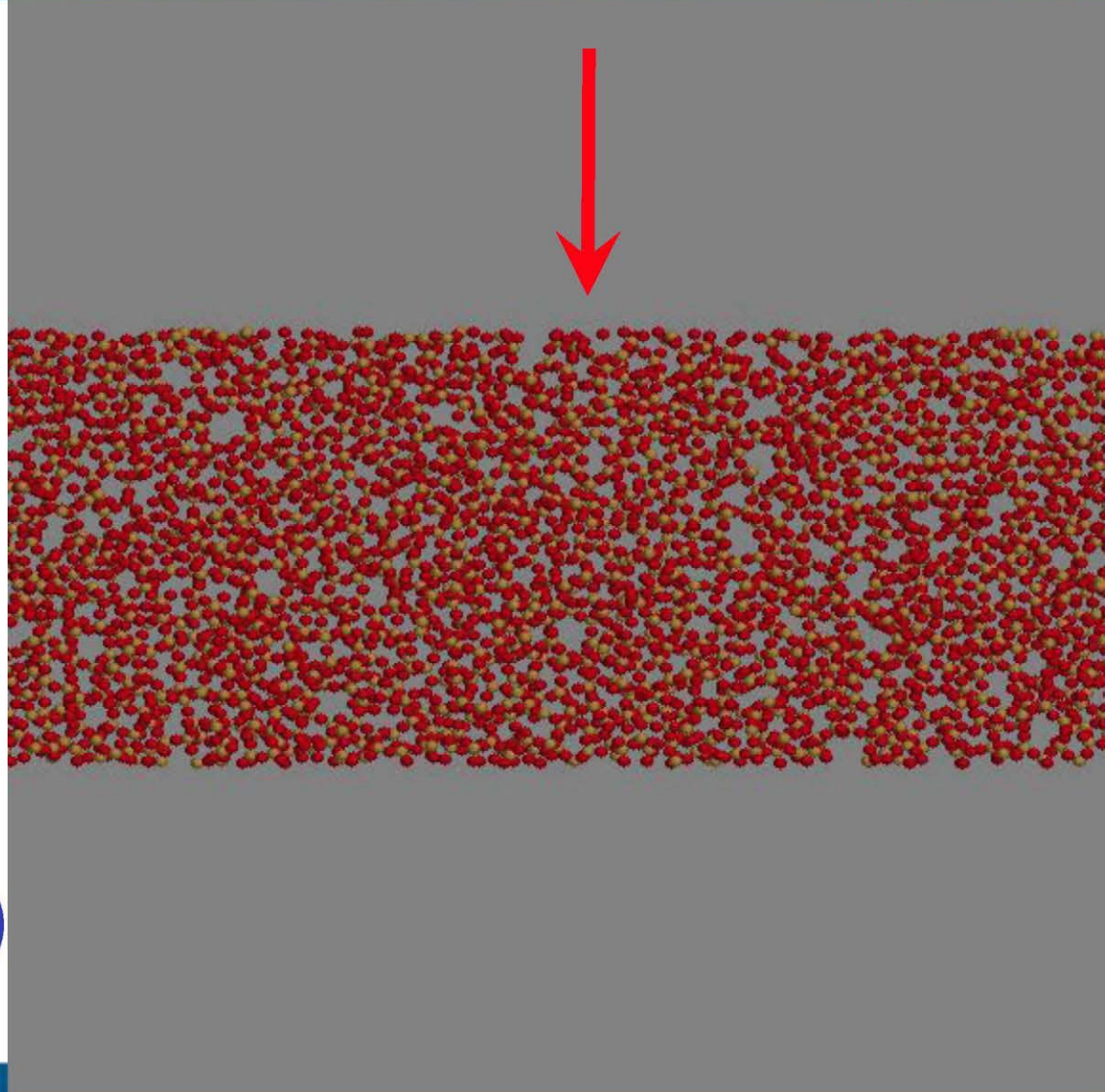
12 keV/nm

- Ion irradiation strongly affects the material
- Density change
- Refractive index
- Defects
- Network structure
- Electronic sputtering (surface)

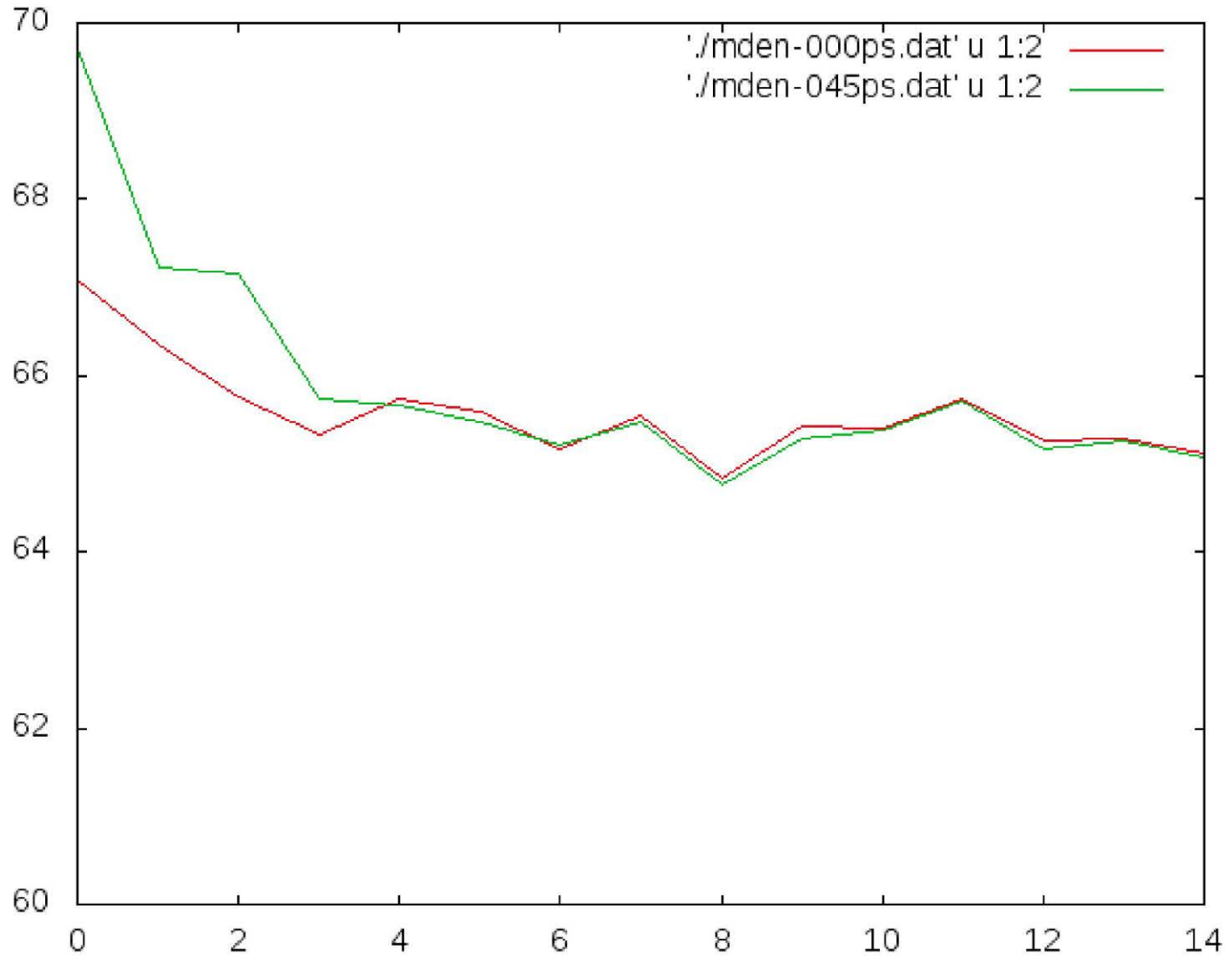


30 keV/nm

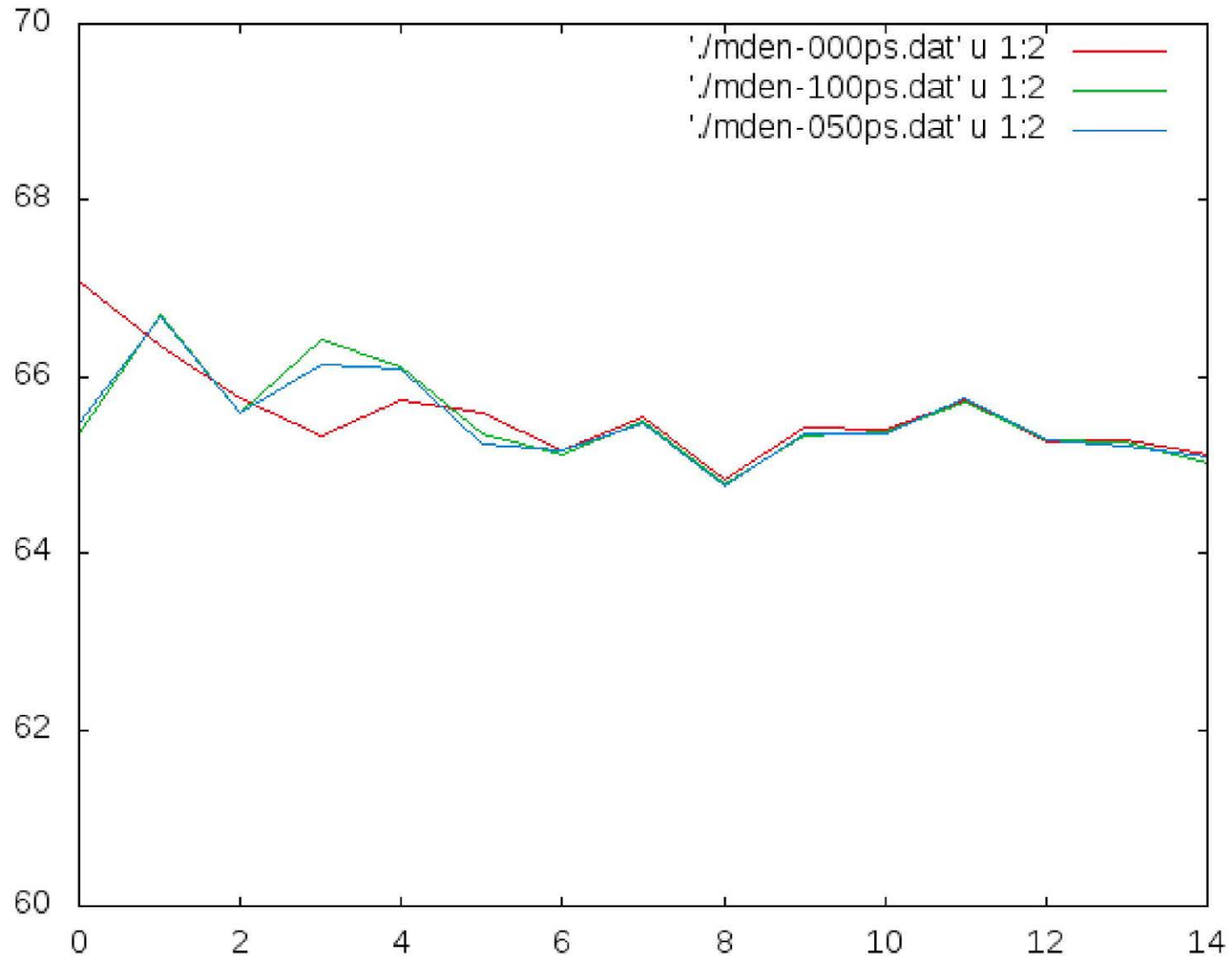
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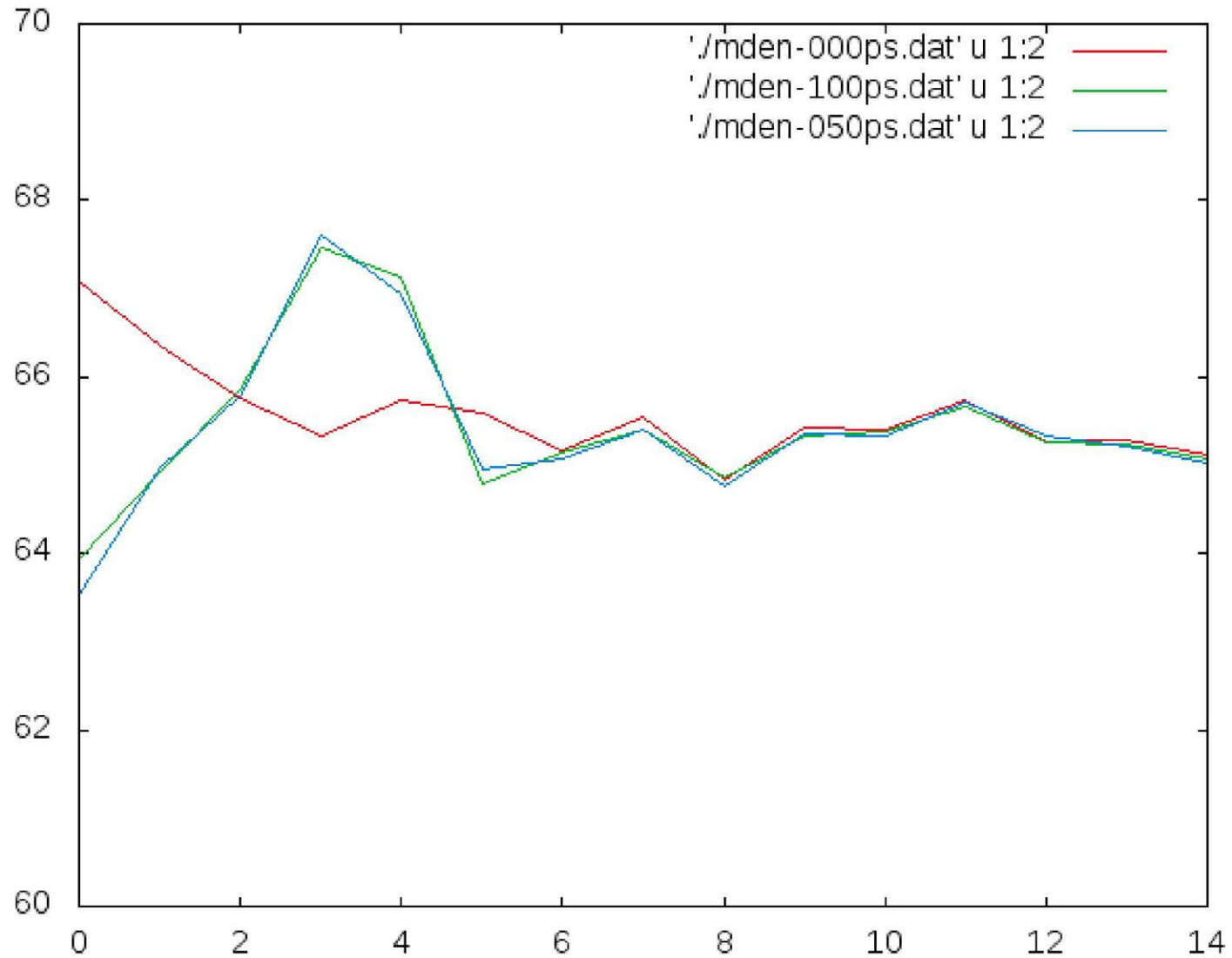
10 keV/nm



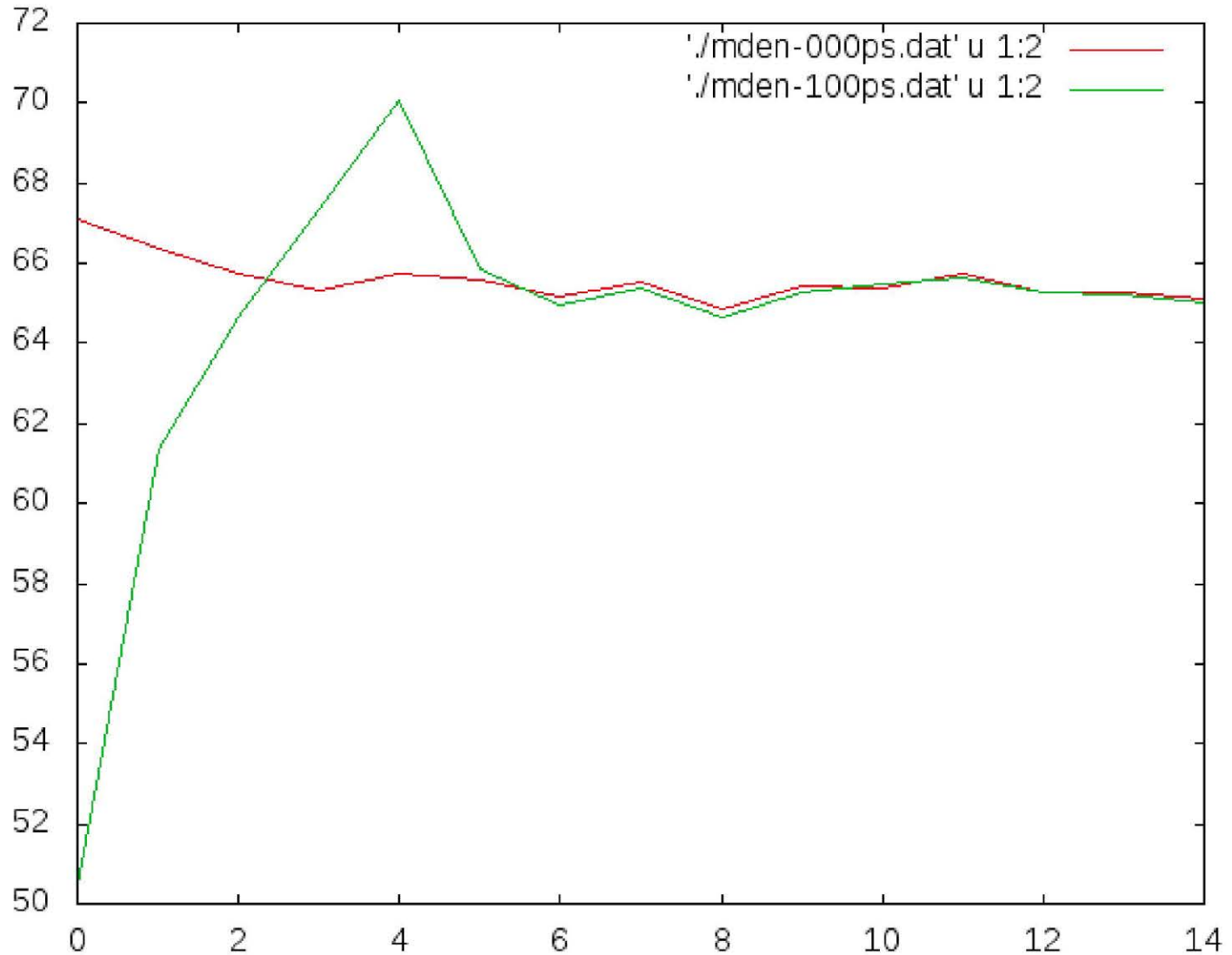
12 keV/nm



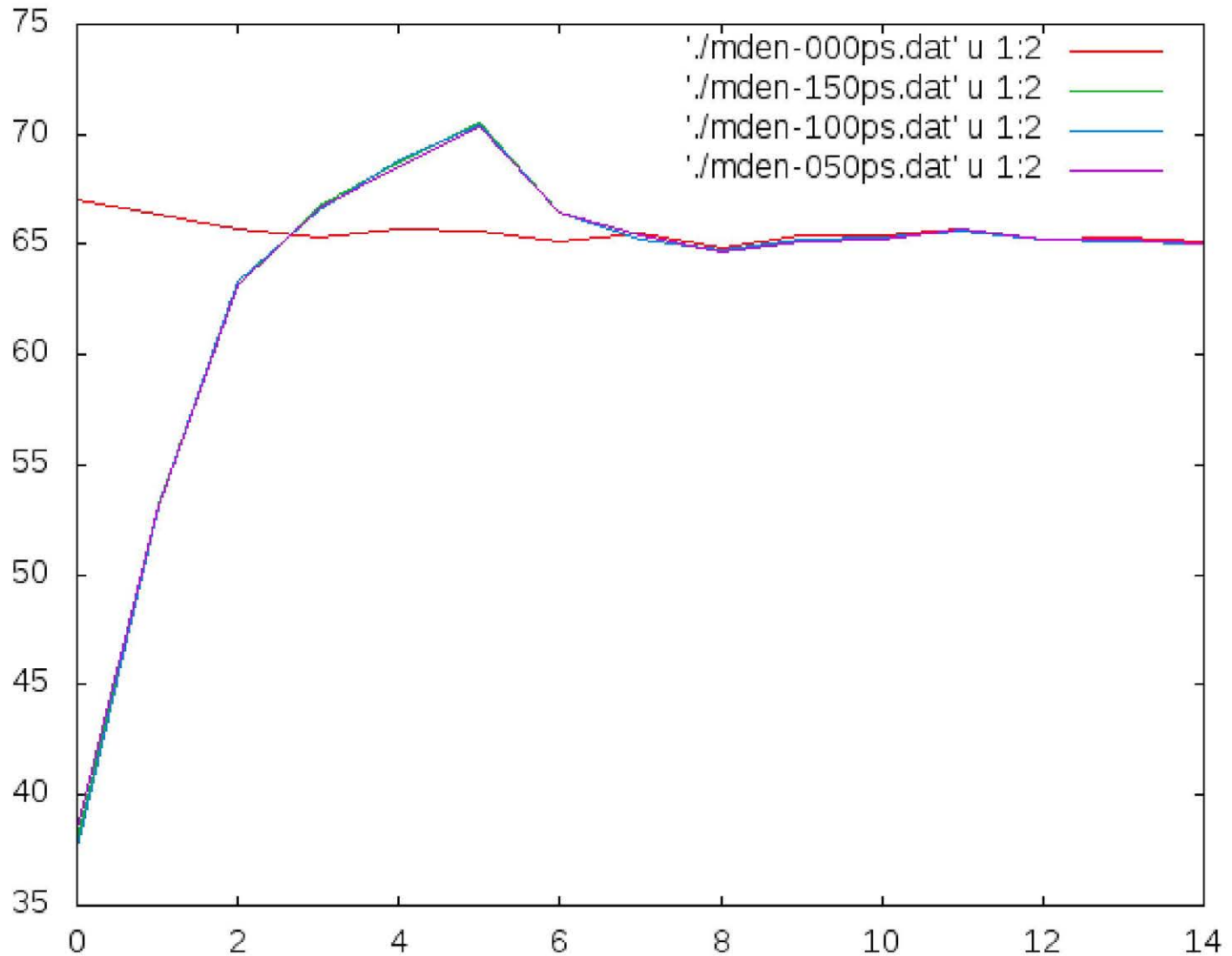
14 keV/nm

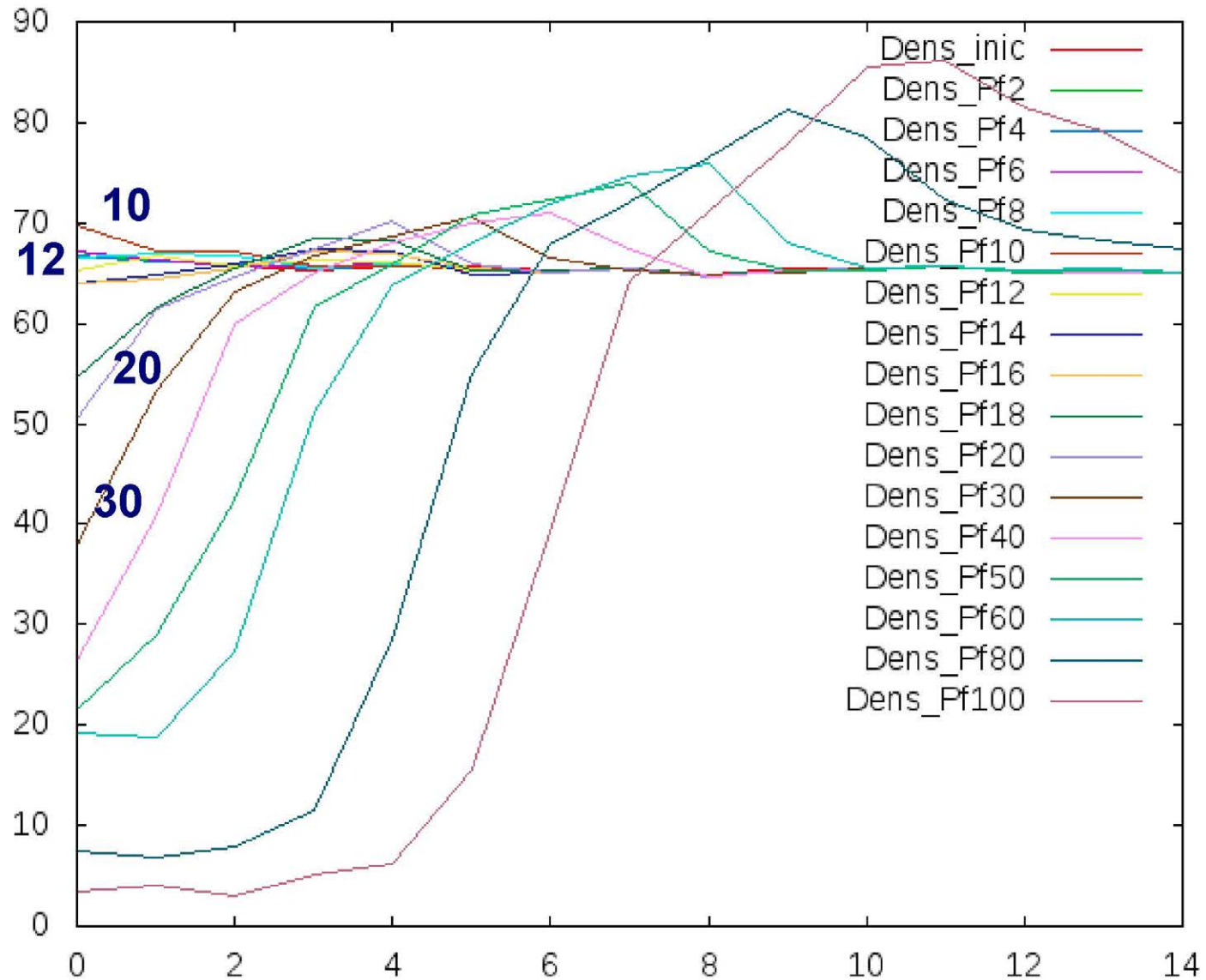


20 keV/nm

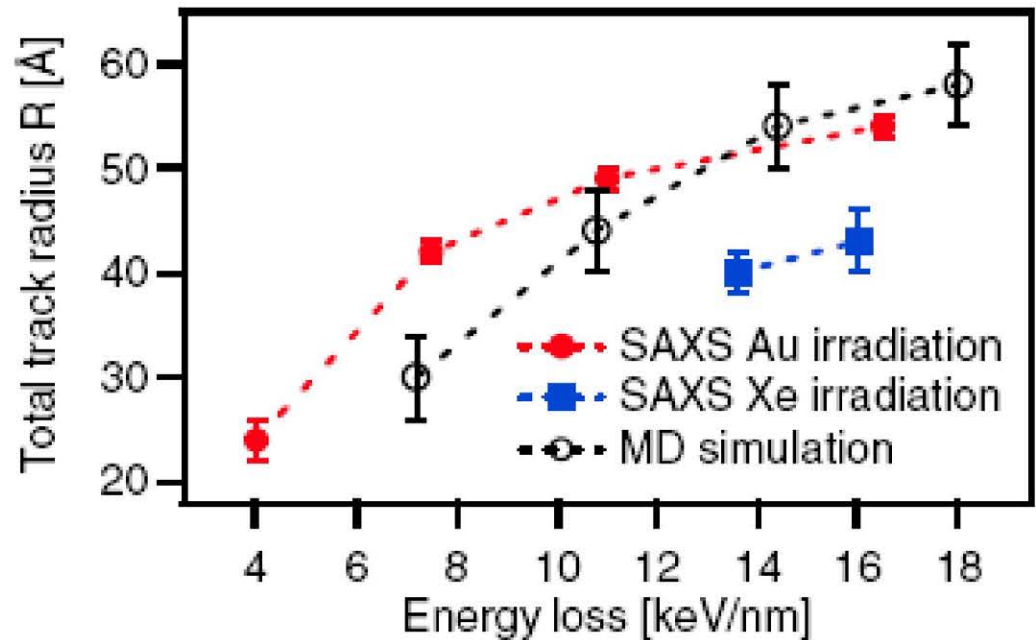


30 keV/nm



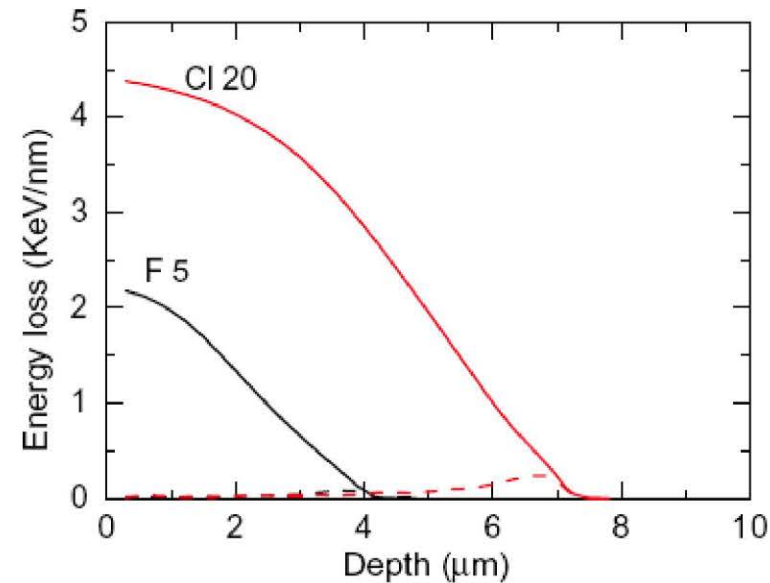
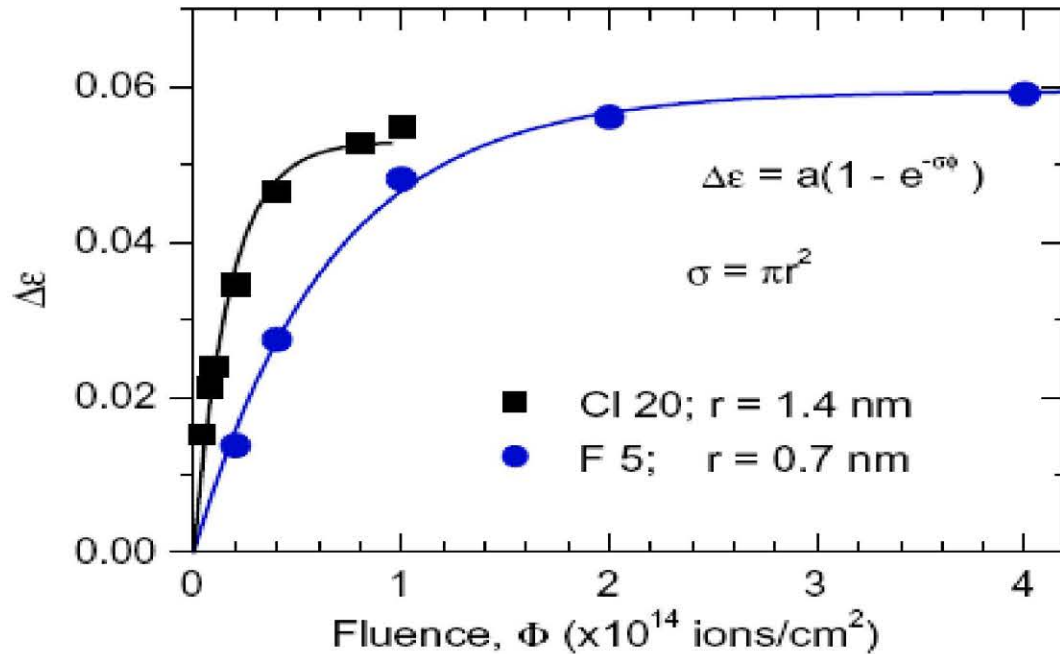


- Previous experimental and MD work show similar effects

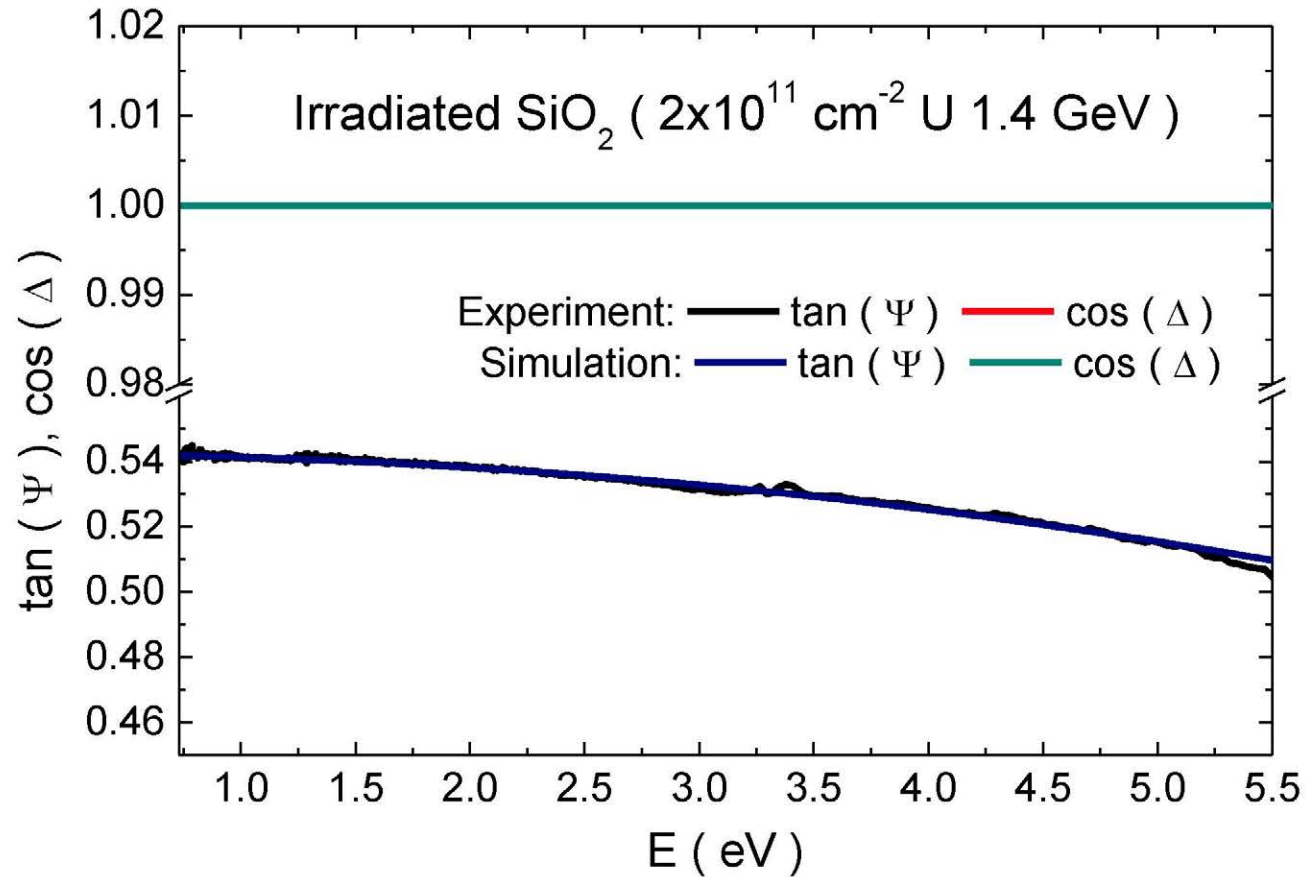


Kluth et al. PRL 101 (2008) 175503

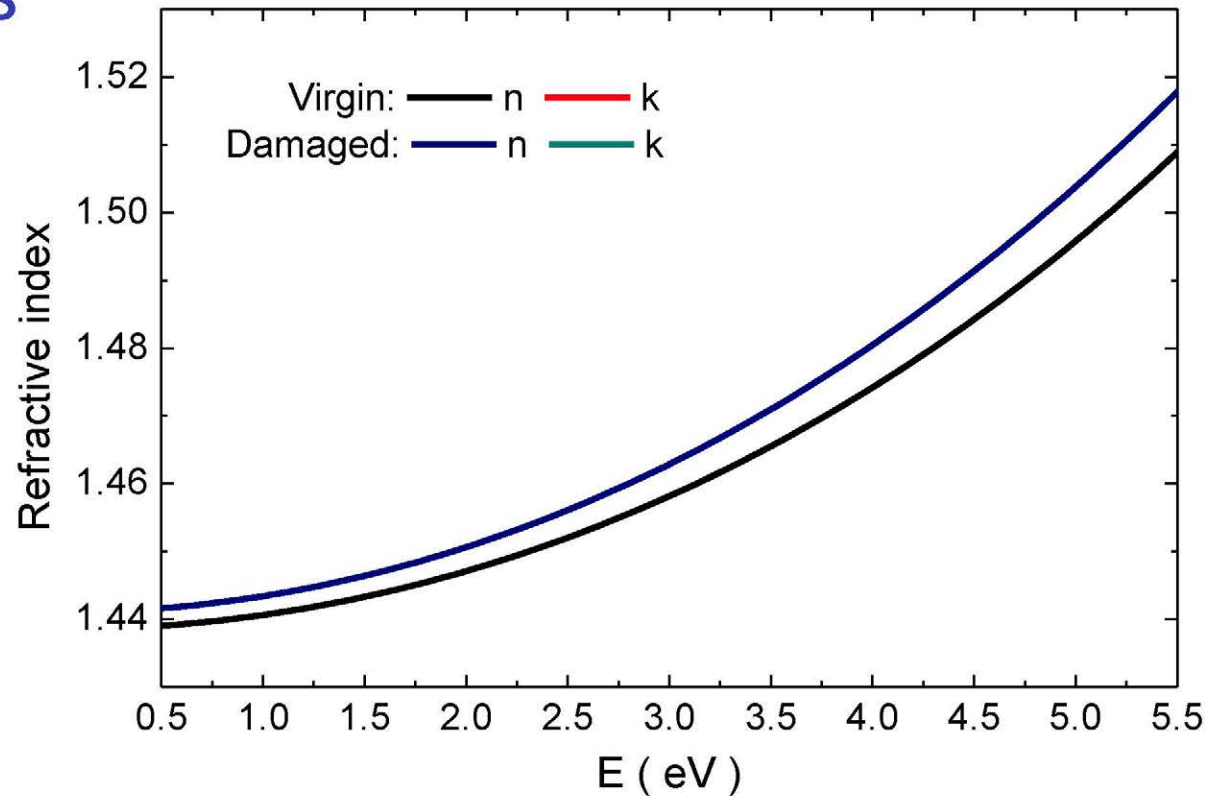
- Low ion energy leads to guided modes by track overlapping



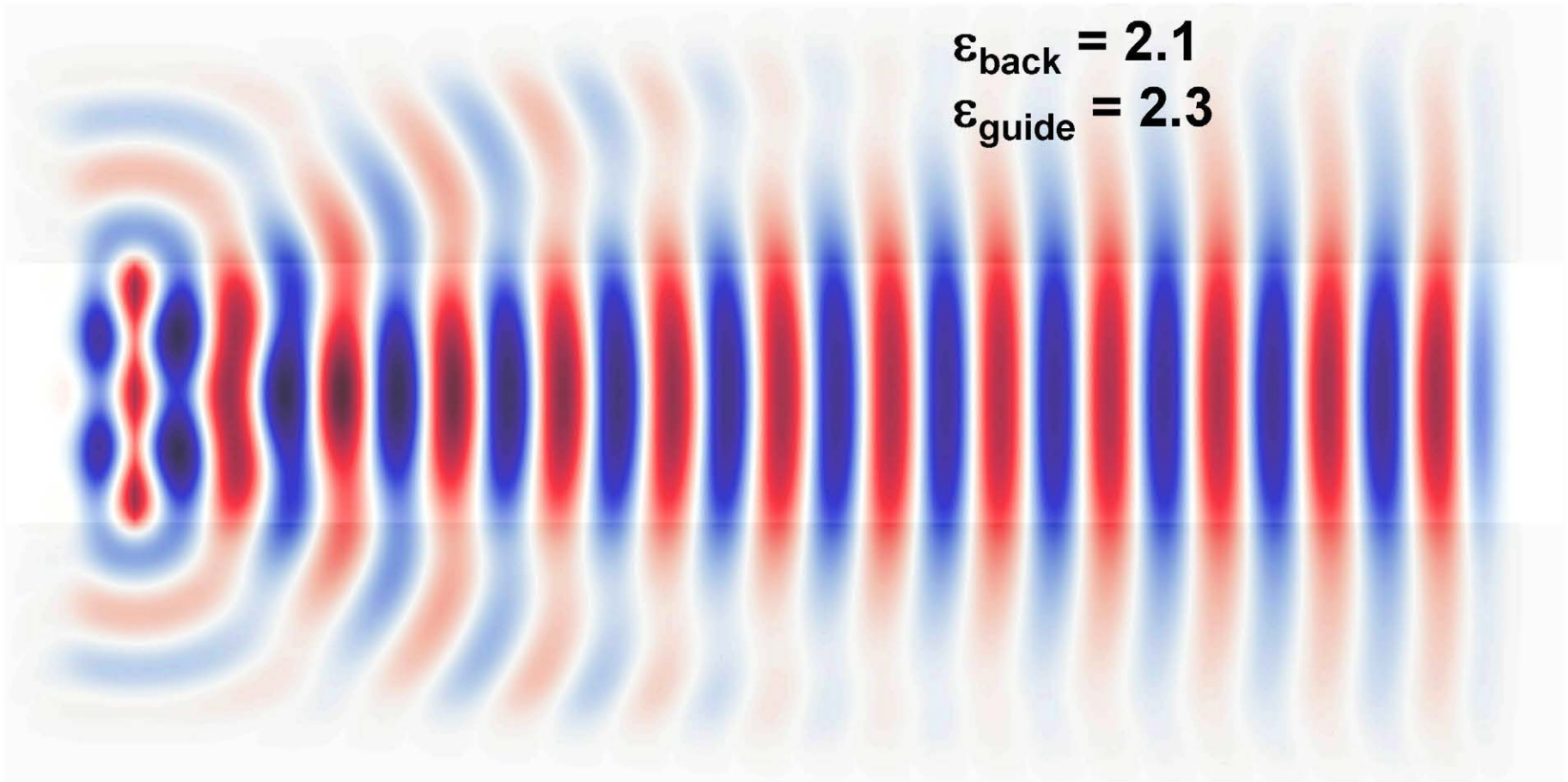
Silica sample
U 1.4 GeV
 $S_e = 35$ keV/nm
 2×10^{11} ions/cm²



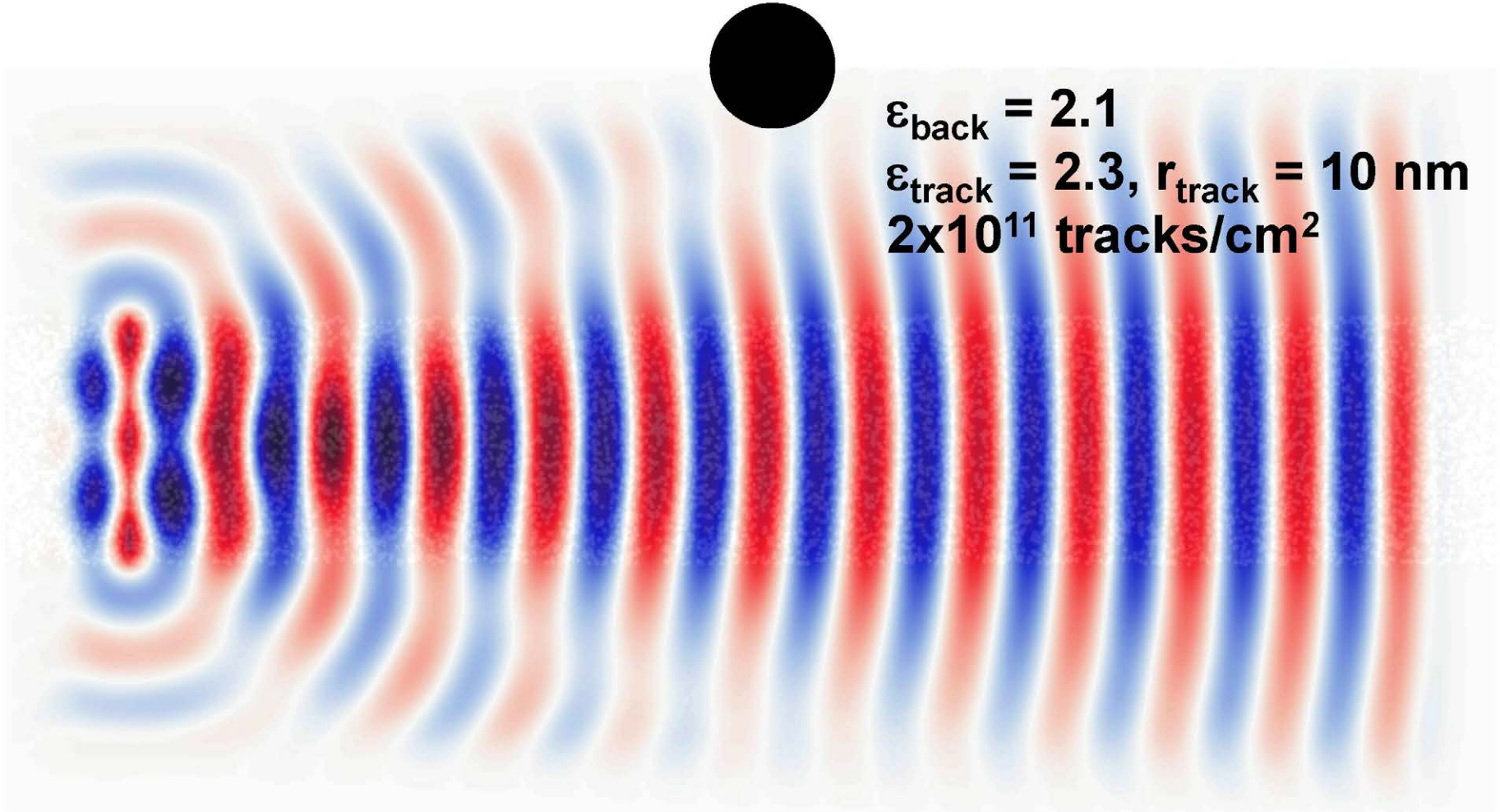
- High energy ions produce large complex tracks
- The result is an effective medium able to guide modes



Full guide (FDTD MEEP)



Solid tracks (FDTD MEEP)



$$\epsilon_{\text{back}} = 2.1$$

$$\epsilon_{\text{track}} = 2.3, r_{\text{track}} = 10 \text{ nm}$$

$$2 \times 10^{11} \text{ tracks/cm}^2$$

Core-shell tracks (FDTD MEEP)

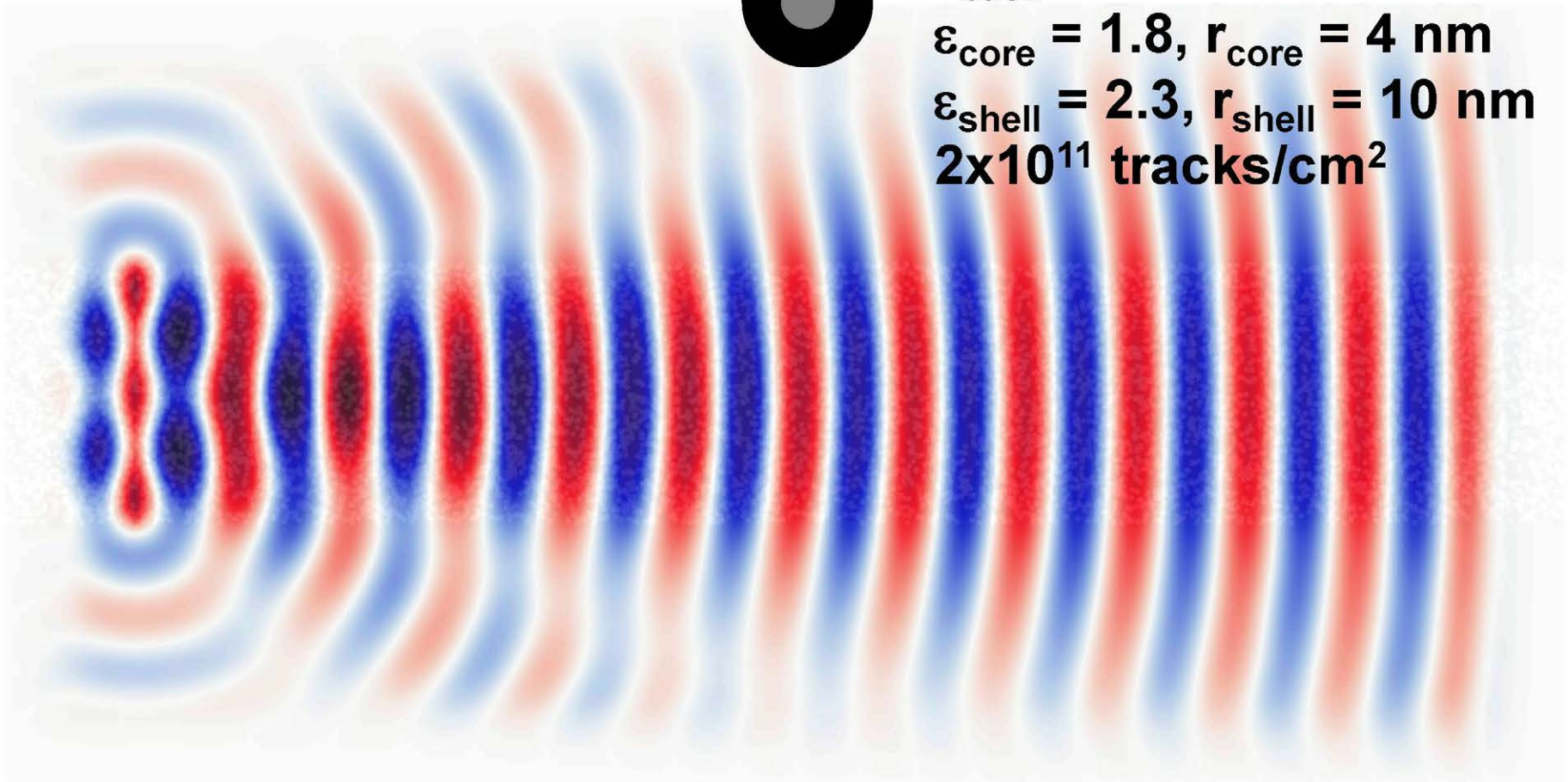


$$\epsilon_{\text{back}} = 2.1$$

$$\epsilon_{\text{core}} = 1.8, r_{\text{core}} = 4 \text{ nm}$$

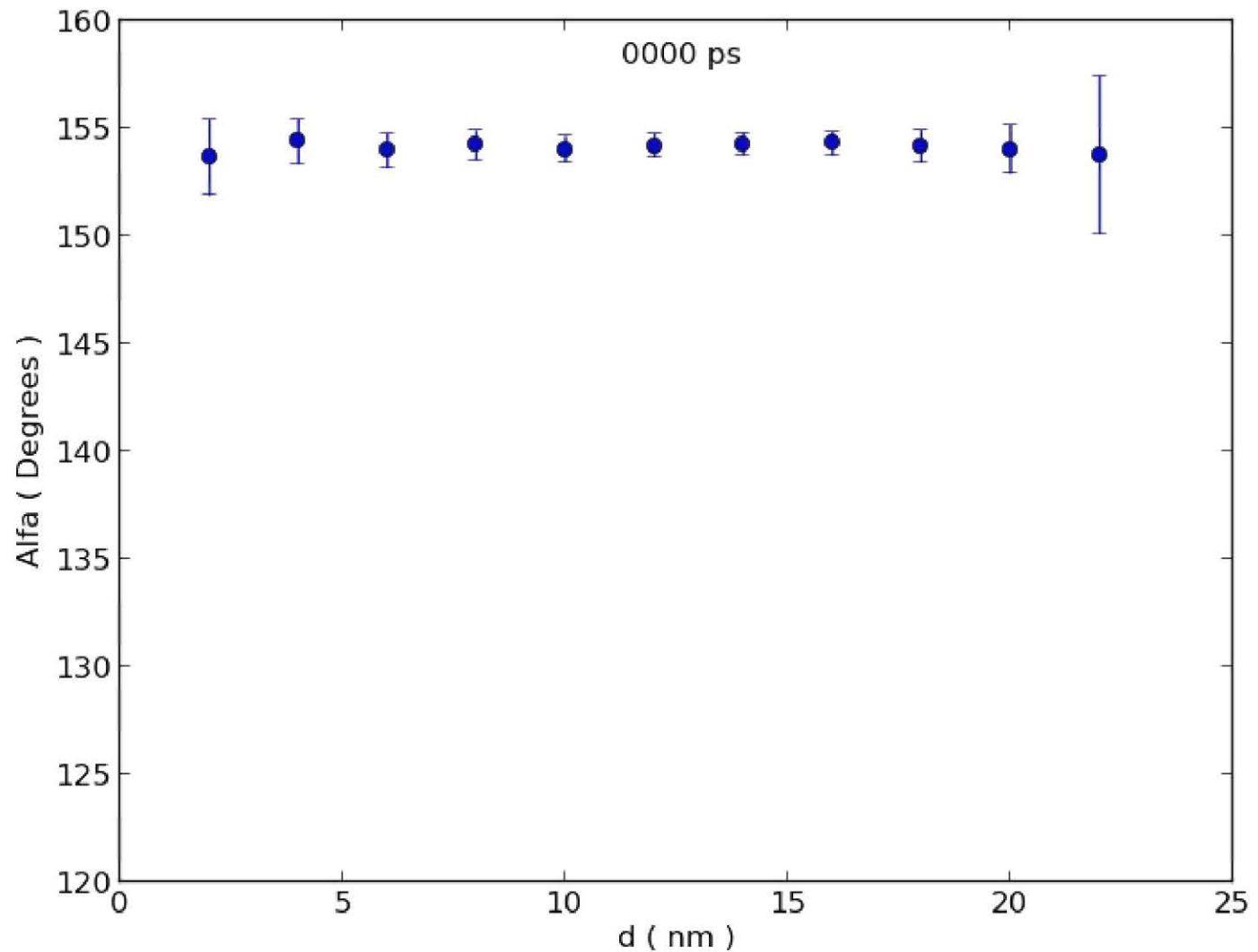
$$\epsilon_{\text{shell}} = 2.3, r_{\text{shell}} = 10 \text{ nm}$$

$$2 \times 10^{11} \text{ tracks/cm}^2$$





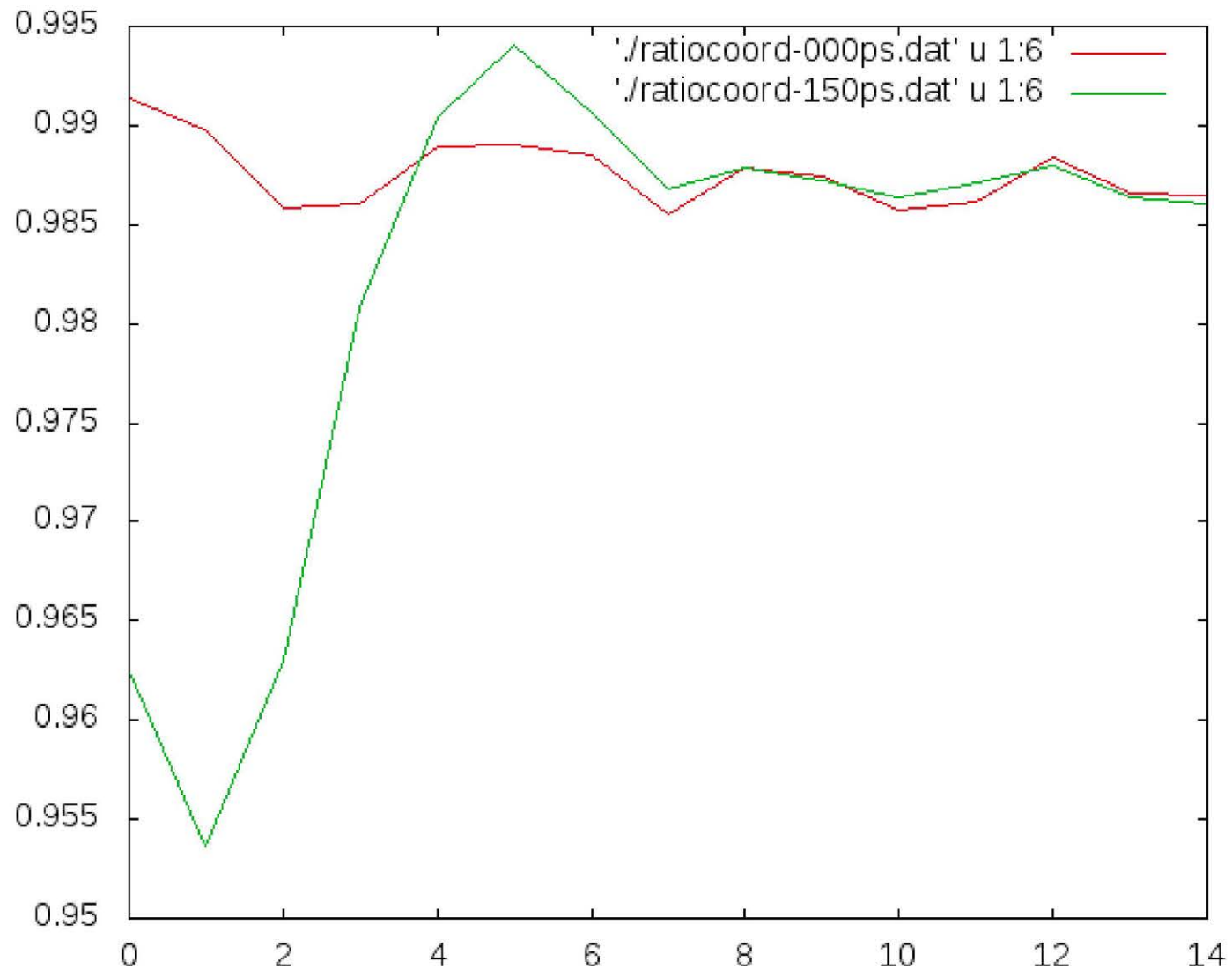
30 keV/nm





30 keV/nm

- At high :
dramma
- Resultir



- At low stopping power the bond structure changes but it recovers
- We can not quantify permanent bond rupture fraction
- Therefore, the origin of permanent defects is unclear

- In order to study thermal effects we have simulated electronic excitation by MD
- Thermal effects on structure, density and defect generation have been identified
- Experiments and FDTD calculations with input from MD show that the tracks are compatible with mode guiding and therefore with refractive index increase
- Defect generation with high stopping power ions can be explained by thermal effects



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Thank you